









SN74AHC126-Q1 SCLS929 - AUGUST 2023

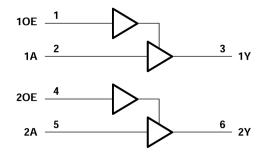
SN74AHC126-Q1 Automotive Quadruple Bus Buffer Gates With 3-State Outputs

1 Features

- AEC-Q100 qualified for automotive applications:
 - Device temperature grade 1: -40°C to +125°C
 - Device HBM ESD classification level 2
 - Device CDM ESD classification level C4B
- Available in wettable flank QFN (WBQA) package
- Operating range 2-V to 5.5-V V_{CC}
- Low delay, 4.3 ns typical (25°C, 5 V)
- Latch-up performance exceeds 250 mA per JESD 17

2 Applications

- **Drive indicator LEDs**
- Drive transmission lines with logic
- Enable or disable a digital signal



3 Description

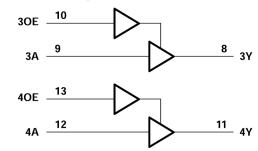
The SN74AHC126-Q1 devices are quadruple bus buffer gates featuring independent line drivers with 3-state outputs.

For the high-impedance state during power up or power down, OE can be tied to GND through a pulldown resistor; the minimum value of the resistor is determined by the current-sourcing capability of the drive.

Package Information

PART NUMBER PACKAGE ⁽¹⁾		PACKAGE SIZE ⁽²⁾	BODY SIZE (NOM) ⁽³⁾	
SN74AHC126-Q1	BQA (WQFN, 14)	3 mm × 2.5 mm	3 mm × 2.5 mm	
	PW (TSSOP, 14)	5 mm × 6.4 mm	5 mm × 4.4 mm	

- For all available packages, see the orderable addendum at (1) the end of the data sheet.
- The package size (length × width) is a nominal value and includes pins, where applicable.
- The body size (length × width) is a nominal value and does not include pins.



Logic Diagram (Positive Logic)



Table of Contents

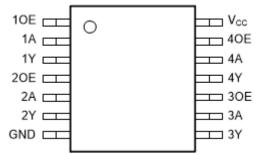
1 Features1	8.1 Overview	. 11
2 Applications1	8.2 Functional Block Diagram	. 11
3 Description1	8.3 Feature Description	.11
4 Revision History2	8.4 Device Functional Modes	.12
5 Pin Configuration and Functions3	9 Application and Implementation	. 13
6 Specifications4	9.1 Application Information	13
6.1 Absolute Maximum Ratings4	9.2 Typical Application	. 13
6.2 ESD Ratings4	9.3 Power Supply Recommendations	.15
6.3 Recommended Operating Conditions5	9.4 Layout	. 15
6.4 Thermal Information5	10 Device and Documentation Support	.16
6.5 Electrical Characteristics6	10.1 Receiving Notification of Documentation Updates	.16
6.6 Switching Characteristics, V _{CC} = 3.3 V ± 0.3 V6	10.2 Support Resources	. 16
6.7 Switching Characteristics, V _{CC} = 5 V ± 0.5 V	10.3 Trademarks	
6.8 Noise Characteristics7	10.4 Electrostatic Discharge Caution	.16
6.9 Operating Characteristics7	10.5 Glossary	.16
6.10 Typical Characteristics8	11 Mechanical, Packaging, and Orderable	
7 Parameter Measurement Information10	Information	. 16
8 Detailed Description11		

4 Revision History

DATE	REVISION	NOTES
August 2023	*	Initial Release



5 Pin Configuration and Functions





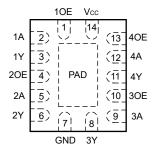


Figure 5-2. BQA Package, WQFN 14-Pin (Transparent Top View)

Table 5-1. Pin Functions

P	IN	TYPE(1)	DESCRIPTION				
NAME	NO.	1116	DESCRIPTION				
10E	1	I	Channel 1, output enable				
1A	2	I	Channel 1, A input				
1Y	3	0	Channel 1, Y output				
20E	4	I	Channel 2, output enable				
2A	5	I	Channel 2, A input				
2Y	6	0	Channel 2, Y output				
GND	7	G	Ground				
3Y	8	0	Channel 3, Y output				
3A	9	I	Channel 3, A input				
30E	10	I	Channel 3, OE input				
4Y	11	0	Channel 4, Y output				
4A	12	I	Channel 4, A input				
40E	13	I	Channel 4, OE input				
V _{CC}	14	Р	Positive supply				
Thermal Page	d ⁽²⁾	_	Thermal pad; connect to GND or leave floating				

- (1) I = input, O = output, P = power, G = ground
- (2) BQA package only



6 Specifications

6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)(1)

			MIN	MAX	UNIT
V _{CC}	Supply voltage range		-0.5	7	V
V _I (2)	Input voltage range		-0.5	7	V
V _O (2)	Output voltage range		-0.5	V _{CC} + 0.5	V
I _{IK}	Input clamp current	(V _I < 0)		-20	mA
I _{OK}	Output clamp current	$(V_O < 0 \text{ or } V_O > V_{CC})$		±20	mA
I _O	Continuous output current	(V _O = 0 to V _{CC})		±25	mA
	Continuous current through V _{CC} or GN	D		±50	mA
T _J	Junction temperature			150	°C
T _{stg}	Storage temperature range		-65	150	°C

⁽¹⁾ Operation outside the *Absolute Maximum Rating* may cause permanent device damage. *Absolute Maximum Rating* do not imply functional operation of the device at these or any other conditions beyond those listed under *Recommended Operating Condition*. If used outside the *Recommended Operating Condition* but within the *Absolute Maximum Rating*, the device may not be fully functional, and this may affect device reliability, functionality, performance, and shorten the device lifetime.

6.2 ESD Ratings

			VALUE	UNIT
V	West Electrostatic discharge	Human body model (HBM), per AEC Q100-002 HBM ESD Classification Level 2 ⁽¹⁾	±2000	\/
v (ESD)		Charged device model (CDM), per AEC Q100-011 CDM ESD Classification Level C4B	±1000	V

(1) AEC Q100-002 indicates that HBM stressing shall be in accordance with the ANSI/ESDA/JEDEC JS-001 specification.

⁽²⁾ The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

6.3 Recommended Operating Conditions

			MIN	MAX	UNIT
V _{CC}	Supply voltage		2	5.5	V
		V _{CC} = 2 V	1.5		
V _{IH}	High-level input voltage	V _{CC} = 3 V	2.1		V
		V _{CC} = 5.5 V	3.85		
V _{IL}		V _{CC} = 2 V		0.5	
	Low-level input voltage	V _{CC} = 3 V		0.9	V
		V _{CC} = 5.5 V		1.65	
V _I ⁽¹⁾	Input voltage		0	5.5	V
Vo	Output voltage		0	V _{CC}	V
		V _{CC} = 2 V		-50	μA
I _{OH} (2)	High-level output current	V _{CC} = 3.3 V ± 0.3 V		-4	m A
		V _{CC} = 5 V ± 0.5 V		-8	mA
		V _{CC} = 2 V		50	μA
I _{OL} (2)	Low-level output current	V _{CC} = 3.3 V ± 0.3 V		4	A
		V _{CC} = 5 V ± 0.5 V		8	mA
	Input transition rice or fell rate	V _{CC} = 3.3 V ± 0.3 V		100	no/\/
Δt/Δv	Input transition rise or fall rate	V _{CC} = 5 V ± 0.5 V		20	ns/V
T _A	Operating free-air temperature		-40	125	°C

⁽¹⁾ All unused inputs of the device must be held at V_{CC} or GND for proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

6.4 Thermal Information

	THERMAL METRIC(1)	WBQA	PW	UNIT	
	THERMAL METRIC	14 PII	14 PINS		
$R_{\theta JA}$	Junction-to-ambient thermal resistance	88.3	151.0		
R _{θJC(top)}	Junction-to-case (top) thermal resistance	90.9	80.0		
$R_{\theta JB}$	Junction-to-board thermal resistance	56.8	94.2	°C/W	
ΨЈТ	Junction-to-top characterization parameter	9.9	28.0	C/VV	
ΨЈВ	Junction-to-board characterization parameter	56.7	93.6		
R _{θJC(bot)}	Junction-to-case (bottom) thermal resistance	33.4	N/A		

(1) For more information about traditional and new thermal metrics, see the IC Package Thermal Metrics application report, SPRA953.

⁽²⁾ Recommended current values provided to maintain appropriate output state as per the relevant output voltage specification (V_{OL} for I_{OL}, V_{OH} for I_{OH}). See *Electrical Characteristics* table for details.

6.5 Electrical Characteristics

over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V	T,	_Δ = 25 °C		-40 to +125 °C		UNIT
PARAMETER	TEST CONDITIONS	V _{cc}	MIN	TYP	MAX	MIN	MAX	UNII
		2 V	1.9	2		1.9		
	I _{OH} = -50 μA	3 V	2.9	3		2.9		
V _{OH}		4.5 V	4.4	4.5		4.4		V
	I _{OH} = -4 mA	3 V	2.58			2.48		
	I _{OH} = -8 mA	4.5 V	3.94			3.8		
		2 V			0.1		0.1	
	I _{OL} = 50 μA	3 V			0.1		0.1	
V _{OL}		4.5 V			0.1		0.1	V
	I _{OL} = 4 mA	3 V			0.36		0.44	
	I _{OL} = 8 mA	4.5 V			0.36		0.44	
I _I	V _I = 5.5 V or GND	0 V to 5.5 V		-	±0.1	-	±1	μA
I _{OZ}	V _I = V _{CC} or GND	5.5 V			±0.25		±2.5	μΑ
I _{CC}	$V_1 = V_{CC} \text{ or } $ $I_O = 0$	5.5 V			4		40	μА
C _i	V _I = V _{CC} or GND	5 V		4	10		10	pF

6.6 Switching Characteristics, V_{CC} = 3.3 V \pm 0.3 V

over recommended operating free-air temperature range, V_{CC} = 3.3 V ± 0.3 V (unless otherwise noted) (see Section 7)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	(OUTPUT) LOAD TA		A = 25°C		-40 to +1	25 °C	UNIT
PARAMETER	PROW (INPUT)	10 (001701)	CAPACITANCE	MIN	TYP	MAX	MIN	MAX	UNII
t _{PLH}	- A	Y	C _L = 15 pF		5.6	8	1	9.5	ns
t _{PHL}	A	1	OL = 13 pr		5.6	8	1	9.5	115
t _{PZH}	OE	Y	C _L = 15 pF		5.4	8	1	9.5	ns
t _{PZL}	OL	'	OL = 13 pi		5.4	8	1	9.5	113
t _{PHZ}	- OE	Y	C _L = 15 pF		7	9.7	1	11.5	ns
t _{PLZ}	OL	•	OL = 13 pi		7	9.7	1	11.5	113
t _{PLH}	Α	Y	C _L = 50 pF		8.1	11.5	1	13	ns
t _{PHL}	^	'	OL = 30 pi		8.1	11.5	1	13	113
t _{PZH}	- OE	Y	C _L = 50 pF		7.9	11.5	1	13	ns
t _{PZL}		1	OL = 30 pi		7.9	11.5	1	13	113
t _{PHZ}	OE	Y	C _L = 50 pF		9.5	13.2	1	15	ns
PLZ		ľ	OL = 30 pr		9.5	13.2	1	15	115
t _{sk(o)}			C _L = 50 pF			1.5		1.5	ns

6.7 Switching Characteristics, $V_{CC} = 5 V \pm 0.5 V$

over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Section 7)

PARAMETER	FROM	TO (OUTPUT)	LOAD	T	A = 25°C		-40 to +1	25 °C	UNIT
PARAWETER	(INPUT)	10 (001P01)	CAPACITANCE	MIN	TYP	MAX	MIN	MAX	UNII
t _{PLH}	А	Υ	C _L = 15 pF		3.8	5.5	1	6.5	ns
t _{PHL}	A	ı	CL = 15 pr		3.8	5.5	1	6.5	115
t _{PZH}	OE	Y	C _L = 15 pF		3.6	5.1	1	6	ns
t _{PZL}	OL	ı	CL = 13 pr		3.6	5.1	1	6	115
t _{PHZ}	OE	Y	C _L = 15 pF		4.6	6.8	1	8	ns
t _{PLZ}	OE	ı	CL = 15 pr		4.6	6.8	1	8	115
t _{PLH}	А	Y	C _L = 50 pF		5.3	7.5	1	8.5	ns
t _{PHL}	^	ı	CL = 30 pr		5.3	7.5	1	8.5	115
t _{PZH}	OE	Y	C _L = 50 pF		5.1	7.1	1	8	ns
t _{PZL}	OL	ı	CL = 30 pr		5.1	7.1	1	8	115
t _{PHZ}	OE	Υ	C _L = 50 pF		6.1	8.8	1	10	ns
t _{PLZ}	OL	ľ	CL = 30 pr		6.1	8.8	1	10	115
t _{sk(o)}			C _L = 50 pF			1		1	ns

6.8 Noise Characteristics

 V_{CC} = 5 V, C_L = 50 pF, T_A = 25° $C^{(1)}$

	PARAMETER	MIN	TYP	MAX	UNIT
V _{OL(P)}	Quiet output, maximum dynamic V _{OL}		0.2	0.8	V
V _{OL(V)}	Quiet output, minimum dynamic V _{OL}	-0.9	-0.2		V
V _{OH(V)}	Quiet output, minimum dynamic V _{OH}	4.4	4.7		V
V _{IH(D)}	High-level dynamic input voltage	3.5			V
V _{IL(D)}	Low-level dynamic input voltage			1.5	V

⁽¹⁾ Characteristics are for surface-mount packages only.

6.9 Operating Characteristics

 V_{CC} = 5 V, T_A = 25°C

	PARAMETER		TEST CONDITIONS	TYP	UNIT
C _{pd}	Power dissipation capacitance	No load,	f = 1 MHz	14	pF



6.10 Typical Characteristics

T_A = 25°C (unless otherwise noted)

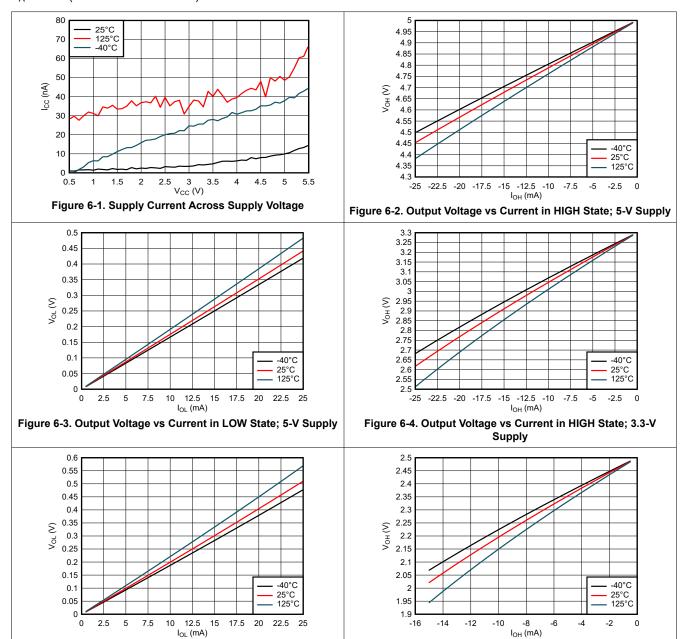


Figure 6-5. Output Voltage vs Current in LOW State; 3.3-V

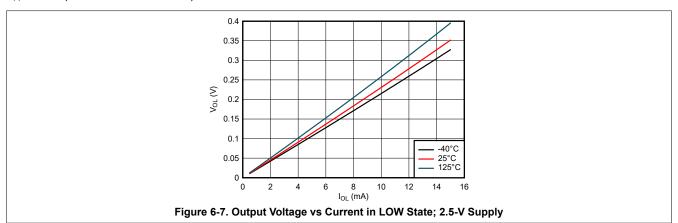
Supply

Figure 6-6. Output Voltage vs Current in HIGH State; 2.5-V

Supply

6.10 Typical Characteristics (continued)

T_A = 25°C (unless otherwise noted)

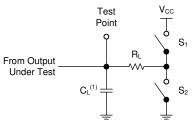


7 Parameter Measurement Information

Phase relationships between waveforms were chosen arbitrarily for the examples listed in the following table. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, Z_O = 50 Ω , t_t < 3 ns.

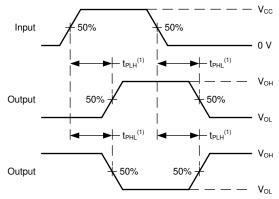
The outputs are measured individually with one input transition per measurement.

TEST	S1	S2	R _L	CL	ΔV	V _{CC}
t _{PLH} , t _{PHL}	OPEN	OPEN	_	15 pF, 50 pF	_	ALL
t _{PLZ} , t _{PZL}	CLOSED	OPEN	1 kΩ	15 pF, 50 pF	0.15 V	≤ 2.5 V
t _{PHZ} , t _{PZH}	OPEN	CLOSED	1 kΩ	15 pF, 50 pF	0.15 V	≤ 2.5 V
t _{PLZ} , t _{PZL}	CLOSED	OPEN	1 kΩ	15 pF, 50 pF	0.3 V	> 2.5 V
t _{PHZ} , t _{PZH}	OPEN	CLOSED	1 kΩ	15 pF, 50 pF	0.3 V	> 2.5 V



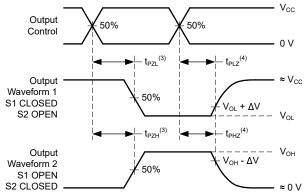
(1) C_I includes probe and test-fixture capacitance.

Figure 7-1. Load Circuit for 3-State Outputs



(1) The greater between t_{PLH} and t_{PHL} is the same as $t_{\text{pd}}.$

Figure 7-2. Voltage Waveforms Propagation Delays



- (3) The greater between $t_{\mbox{\scriptsize PZL}}$ and $t_{\mbox{\scriptsize PZH}}$ is the same as $t_{\mbox{\scriptsize en}}.$
- (4) The greater between t_{PLZ} and t_{PHZ} is the same as t_{dis} .

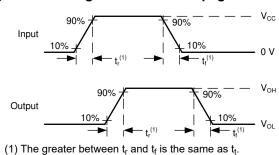
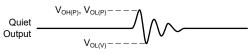


Figure 7-4. Voltage Waveforms, Input and Output Transition Times

Figure 7-3. Voltage Waveforms Propagation Delays



Noise values measured with all other outputs simultaneously switching.

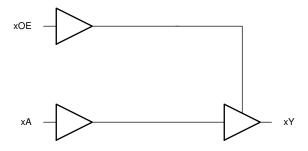
Figure 7-5. Voltage Waveforms, Noise

8 Detailed Description

8.1 Overview

This device contains four independent buffers with 3-state outputs. Each gate performs the Boolean function Y = A in positive logic.

8.2 Functional Block Diagram



One of four channels

8.3 Feature Description

8.3.1 Balanced CMOS 3-State Outputs

This device includes balanced CMOS 3-state outputs. Driving high, driving low, and high impedance are the three states that these outputs can be in. The term *balanced* indicates that the device can sink and source similar currents. The drive capability of this device may create fast edges into light loads, so routing and load conditions should be considered to prevent ringing. Additionally, the outputs of this device can drive larger currents than the device can sustain without being damaged. It is important for the output power of the device to be limited to avoid damage due to overcurrent. The electrical and thermal limits defined in the *Absolute Maximum Ratings* must be followed at all times.

When placed into the high-impedance mode, the output will neither source nor sink current, with the exception of minor leakage current as defined in the *Electrical Characteristics* table. In the high-impedance state, the output voltage is not controlled by the device and is dependent on external factors. If no other drivers are connected to the node, then this is known as a floating node and the voltage is unknown. A pull-up or pull-down resistor can be connected to the output to provide a known voltage at the output while it is in the high-impedance state. The value of the resistor will depend on multiple factors, including parasitic capacitance and power consumption limitations. Typically, a 10-k Ω resistor can be used to meet these requirements.

Unused 3-state CMOS outputs should be left disconnected.

8.3.2 Standard CMOS Inputs

This device includes standard CMOS inputs. Standard CMOS inputs are high impedance and are typically modeled as a resistor in parallel with the input capacitance given in the *Electrical Characteristics*. The worst case resistance is calculated with the maximum input voltage, given in the *Absolute Maximum Ratings*, and the maximum input leakage current, given in the *Electrical Characteristics*, using Ohm's law $(R = V \div I)$.

Standard CMOS inputs require that input signals transition between valid logic states quickly, as defined by the input transition time or rate in the *Recommended Operating Conditions* table. Failing to meet this specification will result in excessive power consumption and could cause oscillations. More details can be found in *Implications of Slow or Floating CMOS Inputs*.

Do not leave standard CMOS inputs floating at any time during operation. Unused inputs must be terminated at V_{CC} or GND. If a system will not be actively driving an input at all times, then a pull-up or pull-down resistor can be added to provide a valid input voltage during these times. The resistor value will depend on multiple factors; a $10\text{-k}\Omega$ resistor, however, is recommended and will typically meet all requirements.



8.3.3 Wettable Flanks

This device includes wettable flanks for at least one package. See the *Features* section on the front page of the data sheet for which packages include this feature.

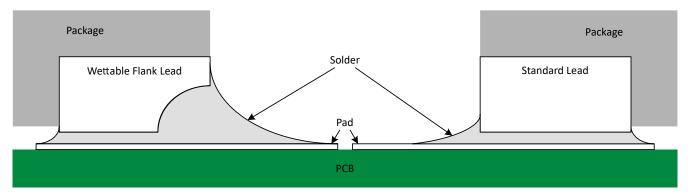


Figure 8-1. Simplified Cutaway View of Wettable-Flank QFN Package and Standard QFN Package After Soldering

Wettable flanks help improve side wetting after soldering, which makes QFN packages easier to inspect with automatic optical inspection (AOI). As shown in Figure 8-1, a wettable flank can be dimpled or step-cut to provide additional surface area for solder adhesion which assists in reliably creating a side fillet. See the mechanical drawing for additional details.

8.3.4 Clamp Diode Structure

As Figure 8-2 shows, the outputs to this device have both positive and negative clamping diodes, and the inputs to this device have negative clamping diodes only.

CAUTION

Voltages beyond the values specified in the *Absolute Maximum Ratings* table can cause damage to the device. The input and output voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

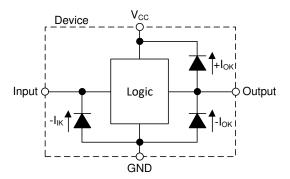


Figure 8-2. Electrical Placement of Clamping Diodes for Each Input and Output

8.4 Device Functional Modes

Table 8-1. Function Table

INP	UTS	OUTPUT
OE	Α	Y
L	Х	Z
Н	L	L
Н	Н	Н

9 Application and Implementation

Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

9.1 Application Information

The SN74AHC126-Q1 can be used to drive signals over relatively long traces or transmission lines. To reduce ringing caused by impedance mismatches between the driver, transmission line, and receiver, a series damping resistor placed in series with the transmitter's output can be used. The figure in the *Application Curve* section shows the received signal with three separate resistor values. Just a small amount of resistance can make a significant impact on signal integrity in this type of application.

9.2 Typical Application

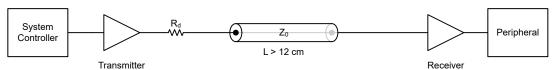


Figure 9-1. Typical Application Block Diagram

9.2.1 Design Requirements

9.2.1.1 Power Considerations

Ensure the desired supply voltage is within the range specified in the *Recommended Operating Conditions*. The supply voltage sets the device's electrical characteristics as described in the *Electrical Characteristics* section.

The positive voltage supply must be capable of sourcing current equal to the total current to be sourced by all outputs of the SN74AHC126-Q1 plus the maximum static supply current, I_{CC} , listed in the *Electrical Characteristics*, and any transient current required for switching. The logic device can only source as much current that is provided by the positive supply source. Be sure to not exceed the maximum total current through V_{CC} listed in the *Absolute Maximum Ratings*.

The ground must be capable of sinking current equal to the total current to be sunk by all outputs of the SN74AHC126-Q1 plus the maximum supply current, I_{CC}, listed in the *Electrical Characteristics*, and any transient current required for switching. The logic device can only sink as much current that can be sunk into its ground connection. Be sure to not exceed the maximum total current through GND listed in the *Absolute Maximum Ratings*.

The SN74AHC126-Q1 can drive a load with a total capacitance less than or equal to 50 pF while still meeting all of the data sheet specifications. Larger capacitive loads can be applied; however, it is not recommended to exceed 50 pF.

The SN74AHC126-Q1 can drive a load with total resistance described by $R_L \ge V_O / I_O$, with the output voltage and current defined in the *Electrical Characteristics* table with V_{OH} and V_{OL} . When outputting in the HIGH state, the output voltage in the equation is defined as the difference between the measured output voltage and the supply voltage at the V_{CC} pin.

Total power consumption can be calculated using the information provided in *CMOS Power Consumption and Cpd Calculation*.

Thermal increase can be calculated using the information provided in *Thermal Characteristics of Standard Linear* and Logic (SLL) Packages and Devices.



CAUTION

The maximum junction temperature, $T_{J(max)}$ listed in the *Absolute Maximum Ratings*, is an additional limitation to prevent damage to the device. Do not violate any values listed in the *Absolute Maximum Ratings*. These limits are provided to prevent damage to the device.

9.2.1.2 Input Considerations

Input signals must cross $V_{IL(max)}$ to be considered a logic LOW, and $V_{IH(min)}$ to be considered a logic HIGH. Do not exceed the maximum input voltage range found in the *Absolute Maximum Ratings*.

Unused inputs must be terminated to either V_{CC} or ground. The unused inputs can be directly terminated if the input is completely unused, or they can be connected with a pull-up or pull-down resistor if the input will be used sometimes, but not always. A pull-up resistor is used for a default state of HIGH, and a pull-down resistor is used for a default state of LOW. The drive current of the controller, leakage current into the SN74AHC126-Q1 (as specified in the *Electrical Characteristics*), and the desired input transition rate limits the resistor size. A 10-k Ω resistor value is often used due to these factors.

The SN74AHC126-Q1 has CMOS inputs and thus requires fast input transitions to operate correctly, as defined in the *Recommended Operating Conditions* table. Slow input transitions can cause oscillations, additional power consumption, and reduction in device reliability.

Refer to the Feature Description section for additional information regarding the inputs for this device.

9.2.1.3 Output Considerations

The positive supply voltage is used to produce the output HIGH voltage. Drawing current from the output will decrease the output voltage as specified by the V_{OH} specification in the *Electrical Characteristics*. The ground voltage is used to produce the output LOW voltage. Sinking current into the output will increase the output voltage as specified by the V_{OL} specification in the *Electrical Characteristics*.

Push-pull outputs that could be in opposite states, even for a very short time period, should never be connected directly together. This can cause excessive current and damage to the device.

Two channels within the same device with the same input signals can be connected in parallel for additional output drive strength.

Unused outputs can be left floating. Do not connect outputs directly to V_{CC} or ground.

Refer to the Feature Description section for additional information regarding the outputs for this device.

9.2.2 Detailed Design Procedure

- Add a decoupling capacitor from V_{CC} to GND. The capacitor needs to be placed physically close to the device and electrically close to both the V_{CC} and GND pins. An example layout is shown in the *Layout* section.
- Ensure the capacitive load at the output is ≤ 50 pF. This is not a hard limit; by design, however, it will
 optimize performance. This can be accomplished by providing short, appropriately sized traces from the
 SN74AHC126-Q1 to one or more of the receiving devices.
- 3. Ensure the resistive load at the output is larger than $(V_{CC} / I_{O(max)}) \Omega$. Doing this will prevent the maximum output current from the *Absolute Maximum Ratings* from being violated. Most CMOS inputs have a resistive load measured in M Ω ; much larger than the minimum calculated previously.
- 4. Thermal issues are rarely a concern for logic gates; the power consumption and thermal increase, however, can be calculated using the steps provided in the application report, CMOS Power Consumption and Cpd Calculation.

Submit Document Feedback

9.2.3 Application Curve

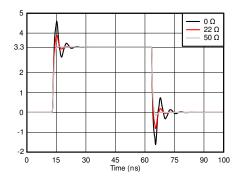


Figure 9-2. Simulated Signal Integrity at the Receiver with Different Damping Resistor (R_d) Values

9.3 Power Supply Recommendations

The power supply can be any voltage between the minimum and maximum supply voltage rating located in the *Recommended Operating Conditions*. Each V_{CC} terminal should have a good bypass capacitor to prevent power disturbance. A 0.1-µF capacitor is recommended for this device. It is acceptable to parallel multiple bypass capacitors to reject different frequencies of noise. The 0.1-µF and 1-µF capacitors are commonly used in parallel. The bypass capacitor should be installed as close to the power terminal as possible for best results.

9.4 Layout

9.4.1 Layout Guidelines

When using multiple-input and multiple-channel logic devices, inputs must never be left floating. In many cases, functions or parts of functions of digital logic devices are unused; for example, when only two inputs of a triple-input AND gate are used or only 3 of the 4 buffer gates are used. Such unused input pins must not be left unconnected because the undefined voltages at the outside connections result in undefined operational states. All unused inputs of digital logic devices must be connected to a logic high or logic low voltage, as defined by the input voltage specifications, to prevent them from floating. The logic level that must be applied to any particular unused input depends on the function of the device. Generally, the inputs are tied to GND or V_{CC}, whichever makes more sense for the logic function or is more convenient.

9.4.2 Layout Example

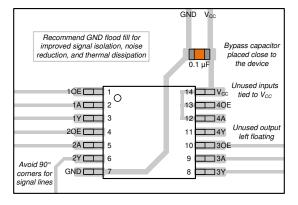


Figure 9-3. Example Layout for the SN74AHC126-Q1

10 Device and Documentation Support

10.1 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Subscribe to updates* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

10.2 Support Resources

TI E2E[™] support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

Linked content is provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

10.3 Trademarks

TI E2E™ is a trademark of Texas Instruments.

All trademarks are the property of their respective owners.

10.4 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

10.5 Glossary

TI Glossary

This glossary lists and explains terms, acronyms, and definitions.

11 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

Submit Document Feedback

www.ti.com 9-Nov-2025

PACKAGING INFORMATION

Orderable part number	Status	Material type	Package Pins	Package qty Carrier	RoHS	Lead finish/ Ball material	MSL rating/ Peak reflow	Op temp (°C)	Part marking (6)
						(4)	(5)		
SN74AHC126QPWRQ1	Active	Production	TSSOP (PW) 14	3000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	AC126Q
SN74AHC126QPWRQ1.A	Active	Production	TSSOP (PW) 14	3000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	AC126Q
SN74AHC126QWBQARQ1	Active	Production	WQFN (BQA) 14	3000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	AC126Q
SN74AHC126QWBQARQ1.A	Active	Production	WQFN (BQA) 14	3000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	AC126Q

⁽¹⁾ Status: For more details on status, see our product life cycle.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

Important Information and Disclaimer: The information provided on this page represents Tl's knowledge and belief as of the date that it is provided. Tl bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. Tl has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. Tl and Tl suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

OTHER QUALIFIED VERSIONS OF SN74AHC126-Q1:

⁽²⁾ Material type: When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

⁽³⁾ RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

⁽⁴⁾ Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

⁽⁵⁾ MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

⁽⁶⁾ Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

PACKAGE OPTION ADDENDUM

www.ti.com 9-Nov-2025

● Catalog : SN74AHC126

• Military : SN54AHC126

NOTE: Qualified Version Definitions:

Catalog - TI's standard catalog product

• Military - QML certified for Military and Defense Applications

PACKAGE MATERIALS INFORMATION

www.ti.com 24-Jul-2025

TAPE AND REEL INFORMATION



TAPE DIMENSIONS + K0 - P1 - B0 W Cavity - A0 -

A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN74AHC126QPWRQ1	TSSOP	PW	14	3000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
SN74AHC126QWBQARQ1	WQFN	BQA	14	3000	180.0	12.4	2.8	3.3	1.1	4.0	12.0	Q1

PACKAGE MATERIALS INFORMATION

www.ti.com 24-Jul-2025



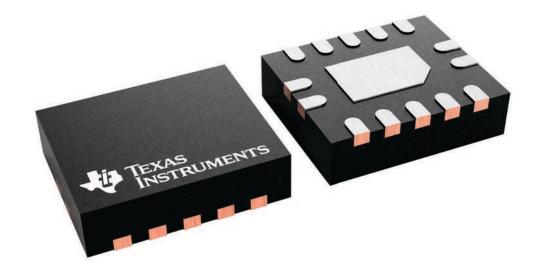
*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN74AHC126QPWRQ1	TSSOP	PW	14	3000	353.0	353.0	32.0
SN74AHC126QWBQARQ1	WQFN	BQA	14	3000	210.0	185.0	35.0

2.5 x 3, 0.5 mm pitch

PLASTIC QUAD FLATPACK - NO LEAD

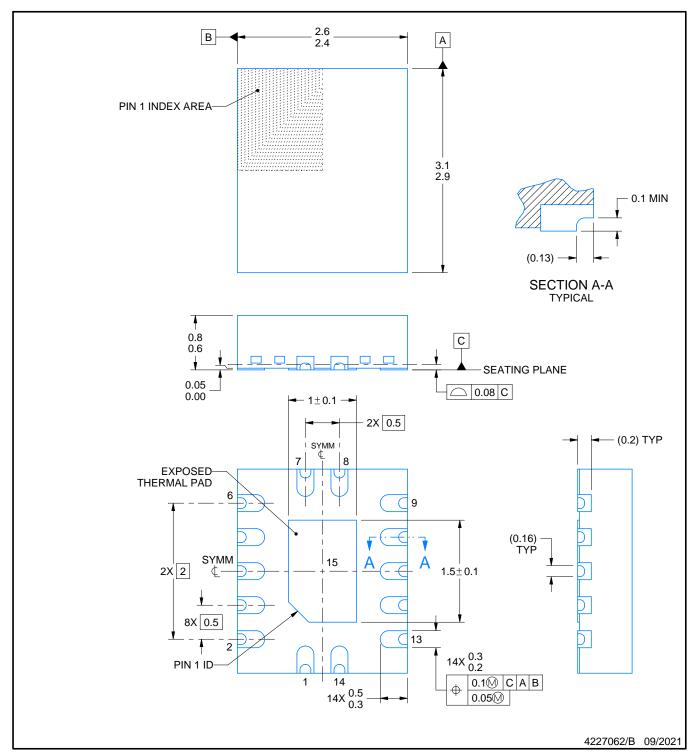
This image is a representation of the package family, actual package may vary. Refer to the product data sheet for package details.



www.ti.com



PLASTIC QUAD FLATPACK - NO LEAD

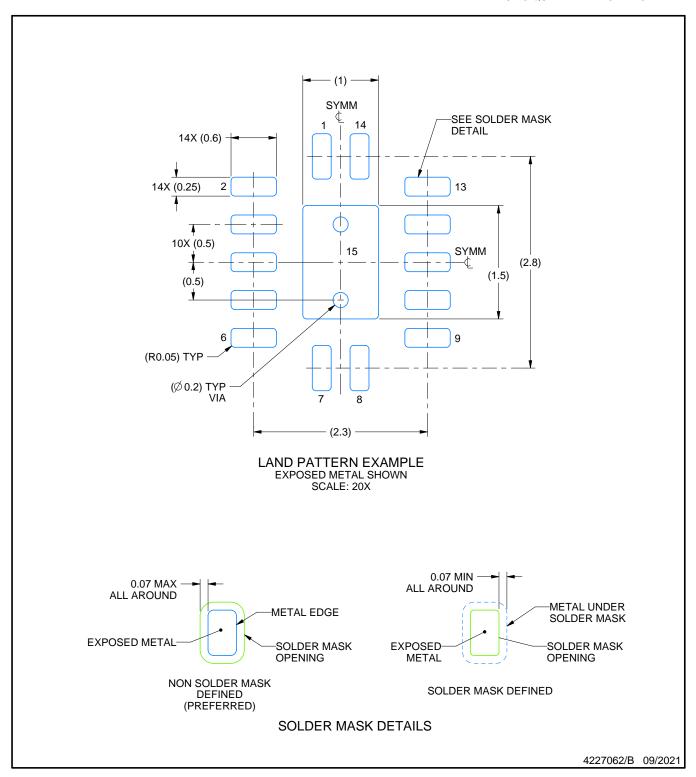


NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
 2. This drawing is subject to change without notice.
- 3. The package thermal pad must be soldered to the printed circuit board for thermal and mechanical performance.



PLASTIC QUAD FLATPACK - NO LEAD

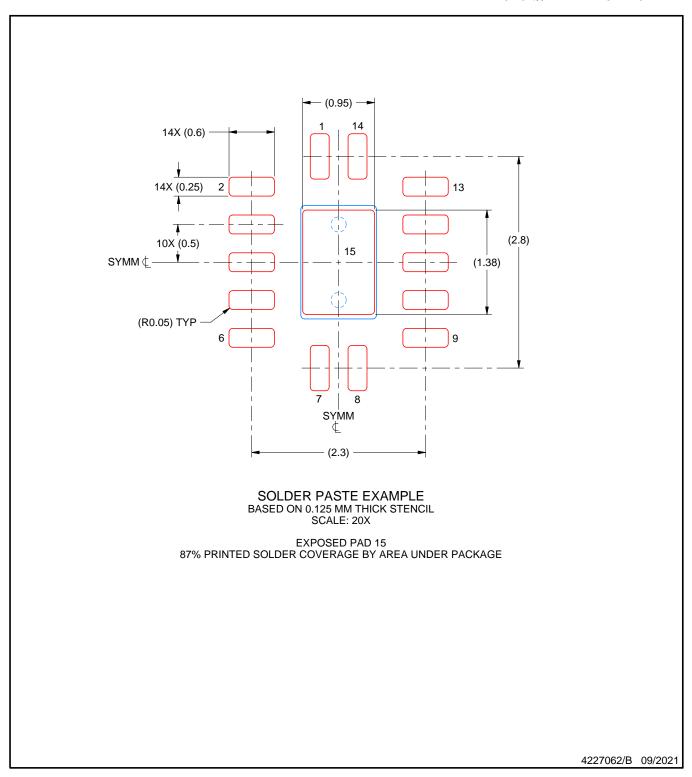


NOTES: (continued)

- 4. This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).
- 5. Vias are optional depending on application, refer to device data sheet. If any vias are implemented, refer to their locations shown on this view. It is recommended that vias under paste be filled, plugged or tented.



PLASTIC QUAD FLATPACK - NO LEAD



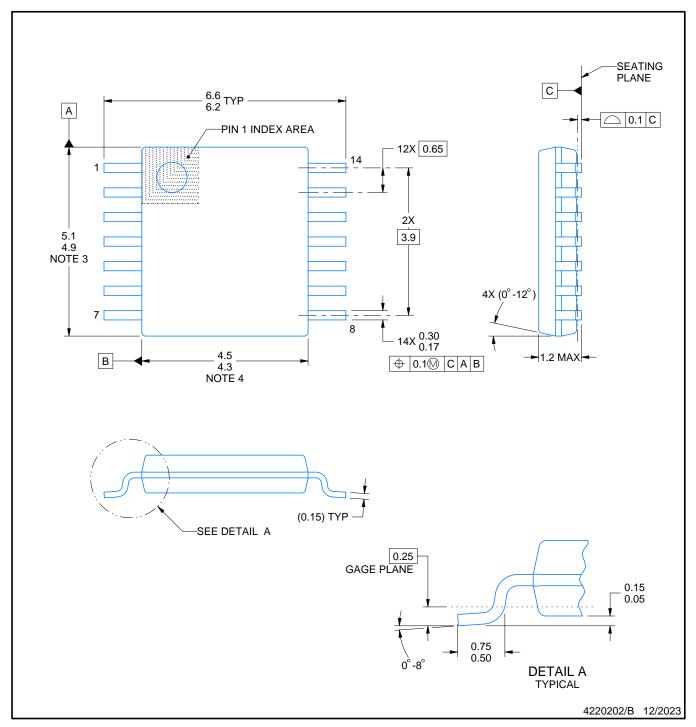
NOTES: (continued)

^{6.} Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.





SMALL OUTLINE PACKAGE



NOTES:

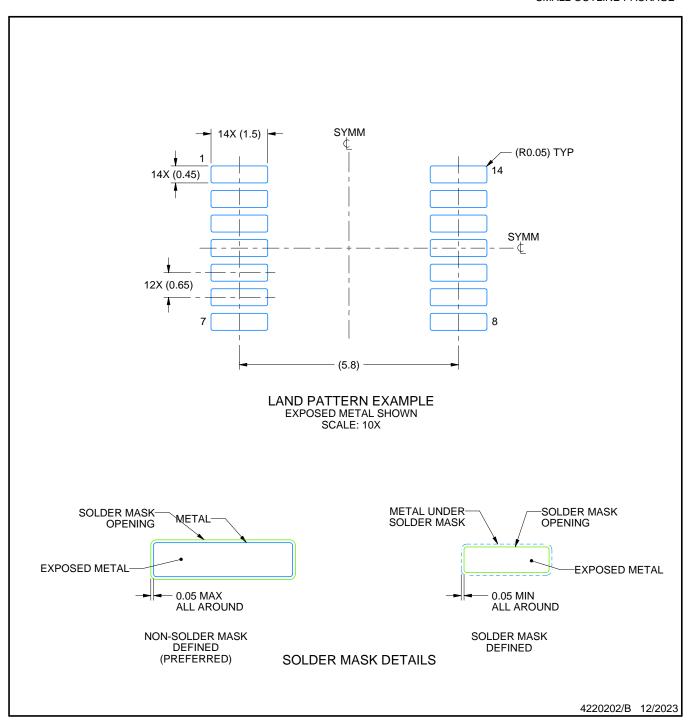
- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153.



SMALL OUTLINE PACKAGE



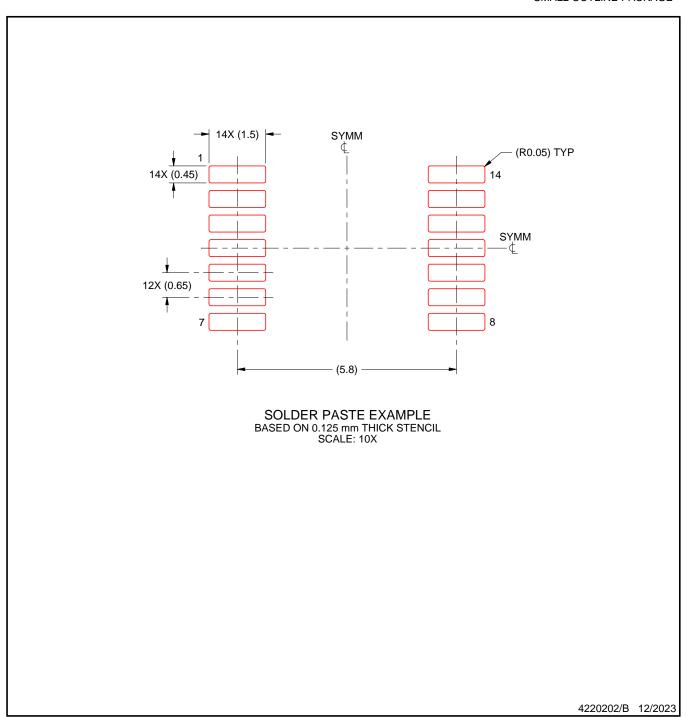
NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE PACKAGE



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



IMPORTANT NOTICE AND DISCLAIMER

TI PROVIDES TECHNICAL AND RELIABILITY DATA (INCLUDING DATASHEETS), DESIGN RESOURCES (INCLUDING REFERENCE DESIGNS), APPLICATION OR OTHER DESIGN ADVICE, WEB TOOLS, SAFETY INFORMATION, AND OTHER RESOURCES "AS IS" AND WITH ALL FAULTS, AND DISCLAIMS ALL WARRANTIES, EXPRESS AND IMPLIED, INCLUDING WITHOUT LIMITATION ANY IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE OR NON-INFRINGEMENT OF THIRD PARTY INTELLECTUAL PROPERTY RIGHTS.

These resources are intended for skilled developers designing with TI products. You are solely responsible for (1) selecting the appropriate TI products for your application, (2) designing, validating and testing your application, and (3) ensuring your application meets applicable standards, and any other safety, security, regulatory or other requirements.

These resources are subject to change without notice. TI grants you permission to use these resources only for development of an application that uses the TI products described in the resource. Other reproduction and display of these resources is prohibited. No license is granted to any other TI intellectual property right or to any third party intellectual property right. TI disclaims responsibility for, and you fully indemnify TI and its representatives against any claims, damages, costs, losses, and liabilities arising out of your use of these resources.

TI's products are provided subject to TI's Terms of Sale, TI's General Quality Guidelines, or other applicable terms available either on ti.com or provided in conjunction with such TI products. TI's provision of these resources does not expand or otherwise alter TI's applicable warranties or warranty disclaimers for TI products. Unless TI explicitly designates a product as custom or customer-specified, TI products are standard, catalog, general purpose devices.

TI objects to and rejects any additional or different terms you may propose.

Copyright © 2025, Texas Instruments Incorporated

Last updated 10/2025